

<b>Notice of References Cited</b>	Application/Control No. 10/564,600		Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner MICHAEL RUTLAND WALLIS		Art Unit 2836	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,770,985	08-2004	Yabe et al.	307/117
*	B	US-7,016,171	03-2006	Bax et al.	361/42
*	C	US-6,294,845	09-2001	Yoshida et al.	307/10.6
*	D	US-6,128,560	10-2000	Ishii, Satoshi	701/29
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.